

High Resolution Transmission Electron Microscopy

HR TEM at Center for Nanoscience & Nanotechnology JMI

High resolution transmission electron microscope is used to characterize the microstructure of materials with very high spatial resolution (0.2nm). It gives the information about the morphology of crystal structure and defects, crystal phases, and composition and magnetic microstructure can be obtained by a combination of education optical imaging, electron diffraction and small probe capabilities.

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